



**Riding the Second Wave of SiC: Power Packaging**

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**Bodo's  
Wide Bandgap  
Event 2024**

*Making WBG Designs Happen*

***SiC***

# Riding the Second Wave of Silicon Carbide (SiC)

## First Wave

SiC die in existing packages

## Second Wave

SiC die in higher performing packages

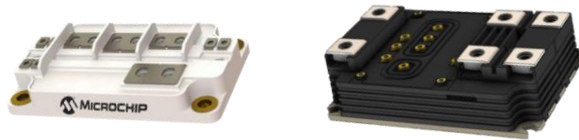
## Third Wave

Higher Voltage SiC Solutions

# Package Importance, Trends and Challenges

- While SiC technology is advancing rapidly, the packaging technology seemed to be relying on the past convention
- Current packaging development pointing to technical challenges
  - Electrical domain: electrical parasitics of the package, gate driver consideration (drain kelvin link)
  - Thermal domain: low SiC die size requires high thermal performance
  - Materials and interconnection: high temperature operations is limited
  - Mechanical domain: pinout design for paralleling, intelligent DC links connection, gate drivers' consideration
  - Problem of second source: slow down adaptation of a new advanced package

Toward high power, symmetrical and low inductance layouts



Toward easy assembly, pinout and layout optimization for various topologies



Toward high semiconductor content integration



TO247-4

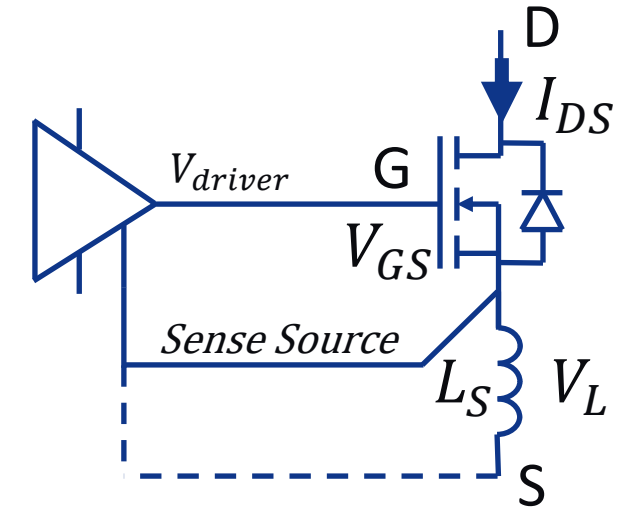
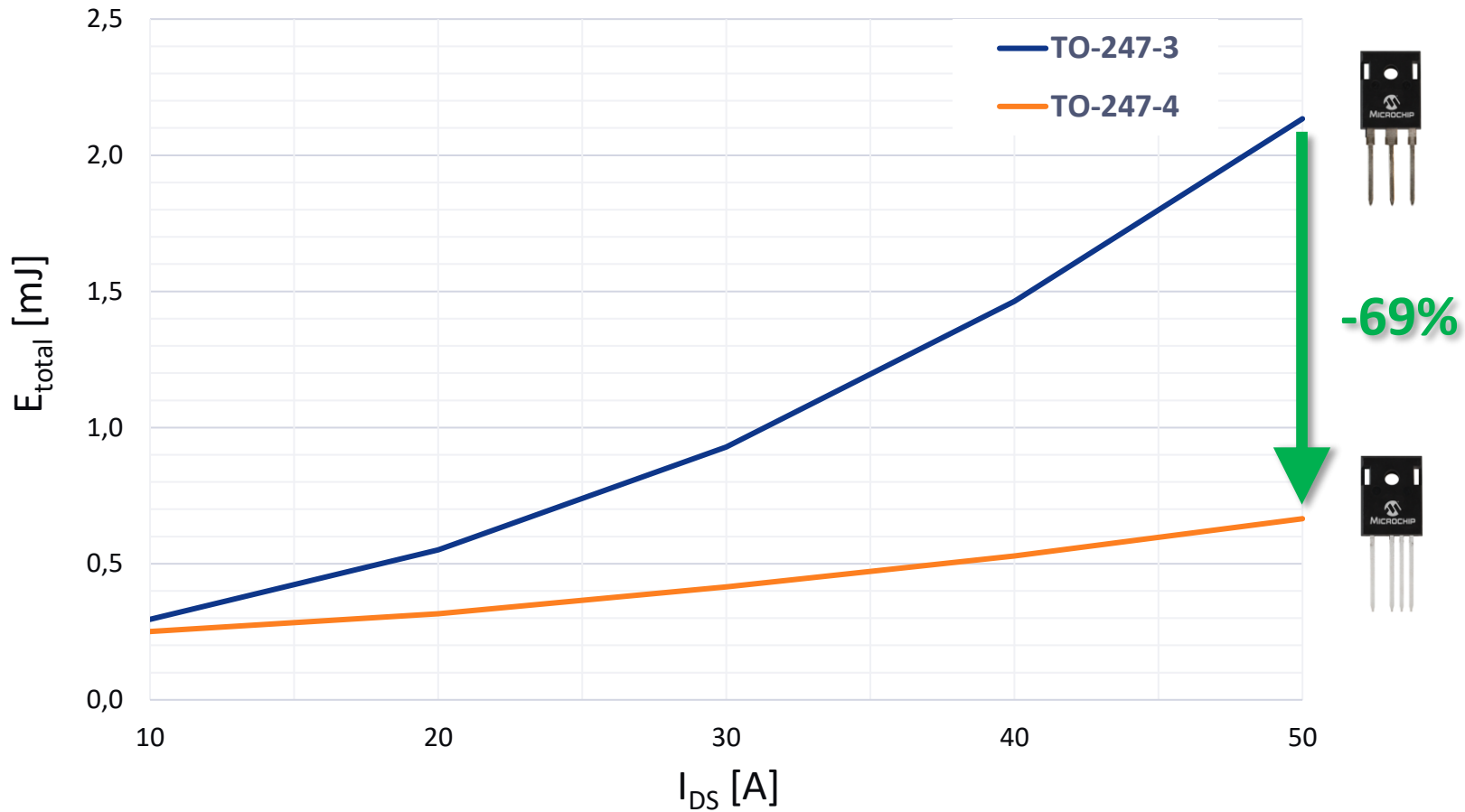




# TO-247 Performance Improvement

## Source sense pin for faster turn on and lower switching losses

1200V, 80 mΩ mSiC™ MOSFET  
 $R_G = 5\Omega$ ,  $V_{DS} = 750V$ ,  $V_{GS} = -5V/20V$ ,  $T_A = 25^\circ C$



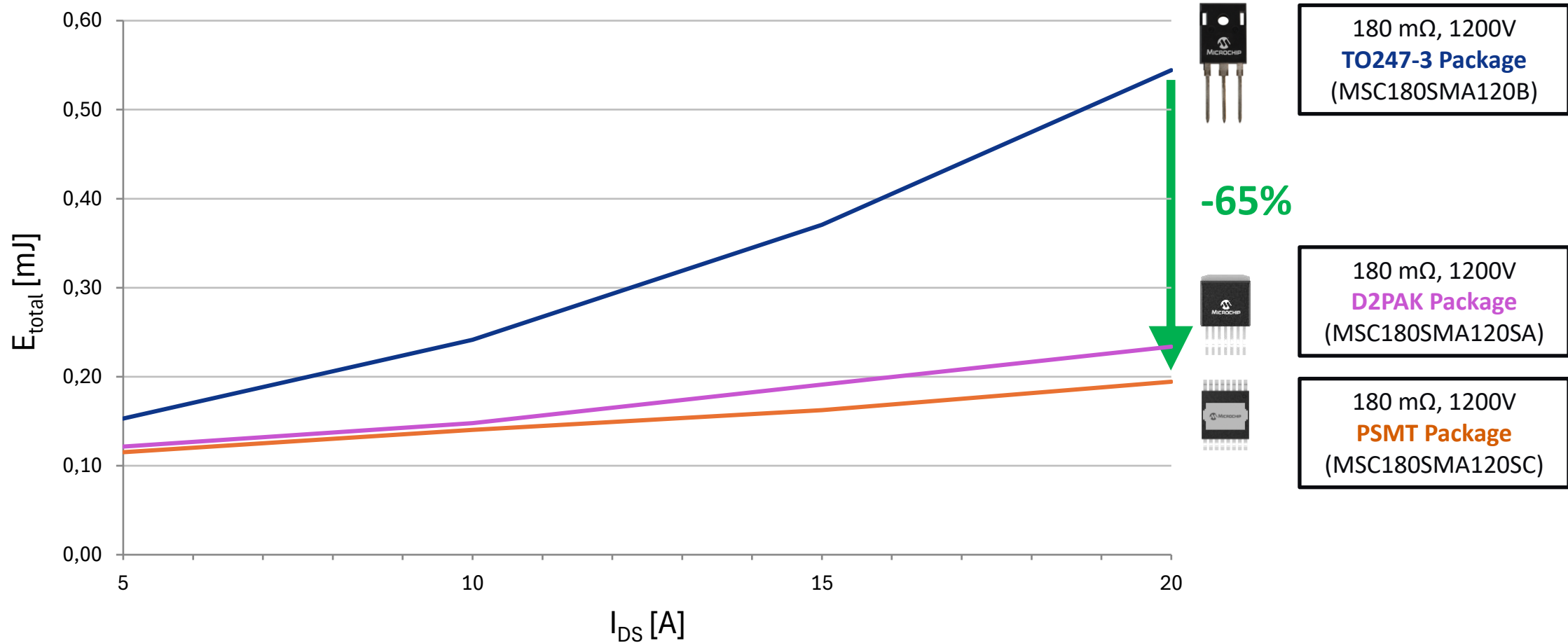
$$V_{GS} = V_{driver} - L_S \frac{dI_{DS}}{dt}$$

$$V_{GS} = V_{driver} - V_L$$

# Pushing Beyond The TO-247

## Source sense pins and top-side cooled

**1200V, 180 m $\Omega$  mSiC™ MOSFET**  
 $R_G = 5\Omega$ ,  $V_{DS} = 800V$ ,  $V_{GS} = -5V/20V$ ,  $T_A = 25^\circ C$



180 m $\Omega$ , 1200V  
**TO247-3 Package**  
(MSC180SMA120B)

-65%



180 m $\Omega$ , 1200V  
**D2PAK Package**  
(MSC180SMA120SA)

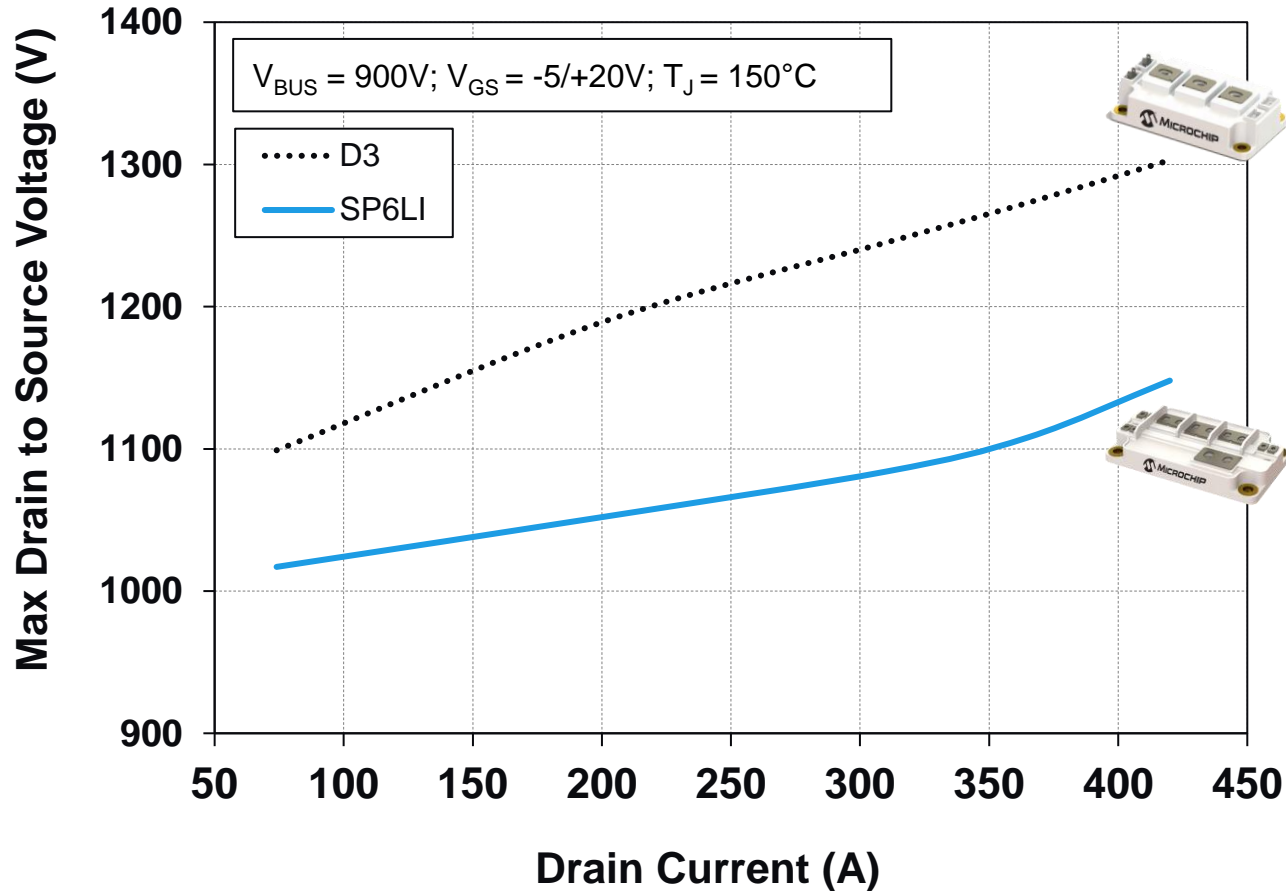


180 m $\Omega$ , 1200V  
**PSMT Package**  
(MSC180SMA120SC)

# Extremely Low Stray Inductance

## Benefit 1 – Reduced voltage overshoot

$V_{DS}$  max vs Drain current



Designers can use lower rated devices and still have margin against overshoot



Lower device cost

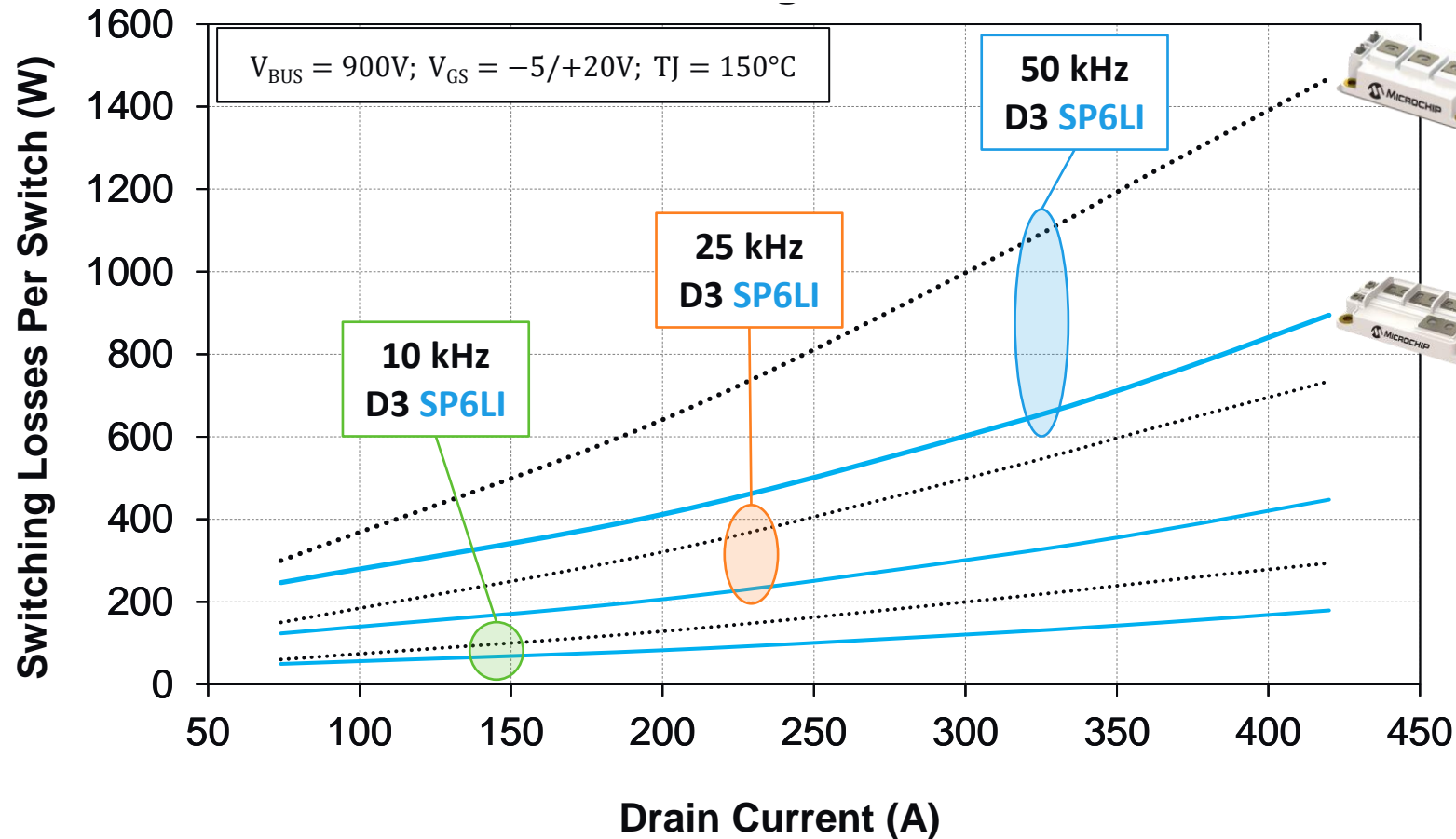


Greater system efficiency

# Extremely Low Stray Inductance

## Benefit 2 – Greater efficiency across wide working conditions

### Switching Losses vs Drain Current

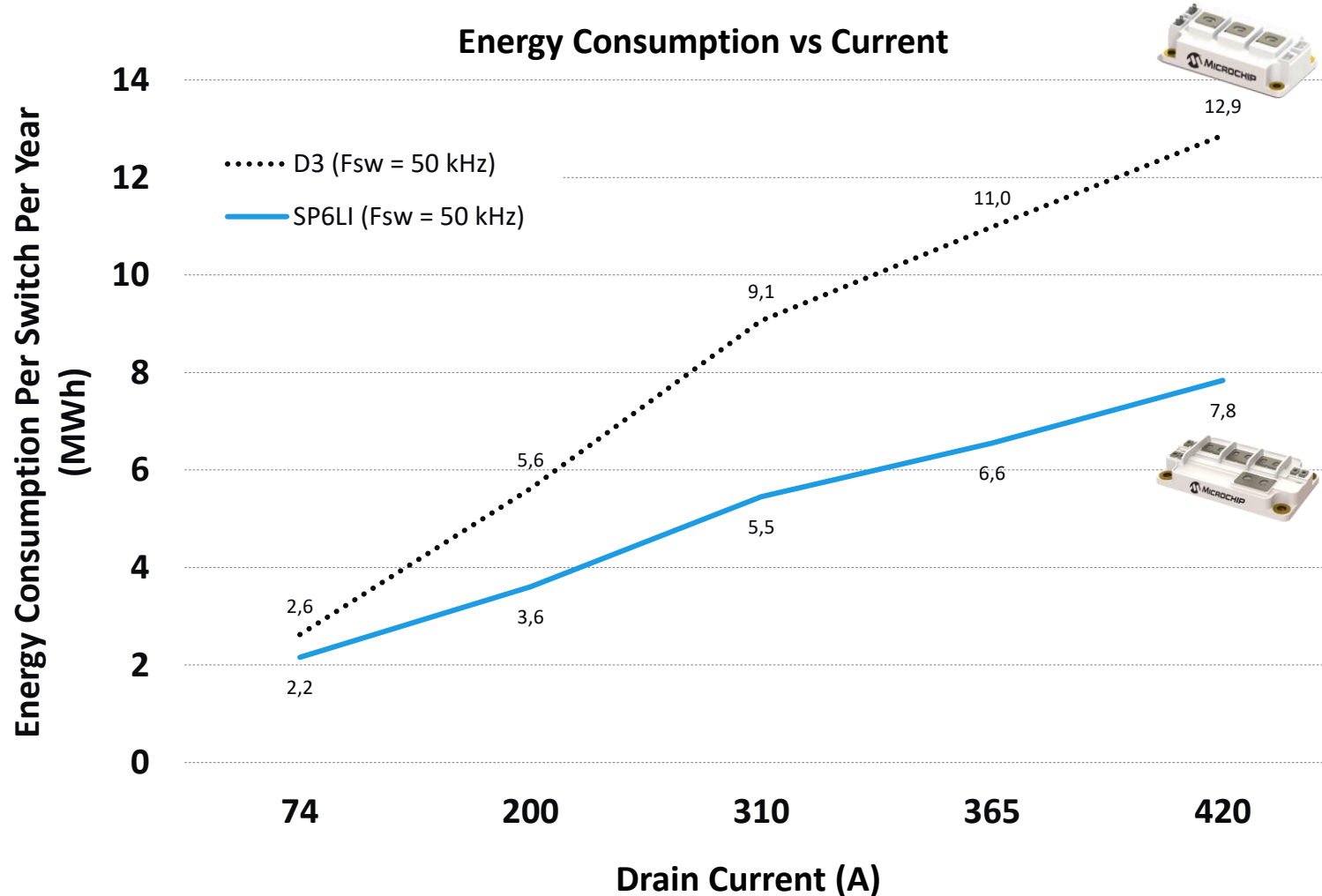


Total switching losses are **20-40% lower**

Effects are more pronounced at higher switching frequency and drain current

# Extremely Low Stray Inductance

## Benefit 3 – Reduced cost of ownership



	10 kHz	25 kHz	50 kHz
D3	2.6	6.4	12.9
SP6LI	1.6	3.9	7.8

Total switching losses per switch per year at 420A, in units of MWhs



# Summary



**Broad market acceptance that SiC saves cost at the system level**



**To get even more out of SiC, new packaging is required to make systems more efficient, compact, and longer-lasting**



**Today we have looked at the impact of parasitic inductance**



**Comparing the SP6LI to the common 62 mm package, the end user can save over \$1,000 per module per year**

# Adopt SiC with Ease, Speed and Confidence

## Contact us at

[www.microchip.com/SiC](http://www.microchip.com/SiC)

